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DB=F	PGPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=YES; OP=OR		
<u>L26</u>	L15 and l13	2	<u>L26</u>
<u>L25</u>	L15 and 112	21	<u>L25</u>
<u>L24</u>	L15 and l11	4	<u>L24</u>
<u>L23</u>	L15 and l10	55	<u>L23</u>
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<u>L19</u>	L15 and 16	7	<u>L19</u>
<u>L18</u>	L15 and 15	128	<u>L18</u>
<u>L17</u>	L15 and 14	2	<u>L17</u>
<u>L16</u>	L15 and l3	128	<u>L16</u>
<u>L15</u>	L14 and l2	989	<u>L15</u>

<u>L14</u>	(time) near4 (division\$5 or multiplex\$4)	108023	<u>L14</u>
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<u>L13</u>	(370/238)[CCLS]	447	<u>L13</u>
<u>L12</u>	(370/230-240)[CCLS]	3725	<u>L12</u>
<u>L11</u>	(710/117,312)[CCLS]	210	<u>L11</u>
<u>L10</u>	(710/300-317)[CCLS]	8047	<u>L10</u>
<u>L9</u>	(711/130-153)![CCLS]	6712	<u>L9</u>
<u>L8</u>	(711/119-173)![CCLS]	14734	<u>L8</u>
<u>L7</u>	(712/13,29)![CCLS]	264	<u>L7</u>
<u>L6</u>	(712/13,29)[CCLS]	264	<u>L6</u>
<u>L5</u>	(712/2-300)[CCLS]	10687	<u>L5</u>
<u>L4</u>	(709/215,241)![CCLS]	439	<u>L4</u>
<u>L3</u>	(709/213-253)![CCLS]	27678	<u>L3</u>
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<u>L1</u>	(common or shar\$6) near4 (memor\$4 or register\$1 or stor\$6 or stack\$1)	47	<u>L1</u>

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